

**Notice of References Cited**

Application/Control No.

10/584,788

Applicant(s)/Patent Under  
Reexamination  
WINZENRIED ET AL.

Examiner

JACOB C. COPPOLA

Art Unit

3621

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0163428 A1	08-2003	Schneck et al.	705/51
*	B	US-2002/0019814 A1	02-2002	Ganesan, Krishnamurthy	705/59
*	C	US-6,772,340 B1	08-2004	Peinado et al.	705/56
*	D	US-6,792,113 B1	09-2004	Ansell et al.	705/57
*	E	US-2005/0027997 A1	02-2005	Ueno et al.	713/193
*	F	US-2005/0132201 A1	06-2005	Pitman et al.	713/176
*	G	US-7,032,240 B1	04-2006	Cronce et al.	705/51
*	H	US-2006/0136735 A1	06-2006	Plotkin et al.	713/182
*	I	US-2006/0174349 A1	08-2006	Cronce et al.	726/026
*	J	US-5,768,389 A	06-1998	Ishii, Shinji	380/30
*	K	US-2002/0138724 A1	09-2002	Aull, Kenneth W.	713/156
*	L	US-7,483,860	01-2009	Cronce et al.	705/50
*	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.